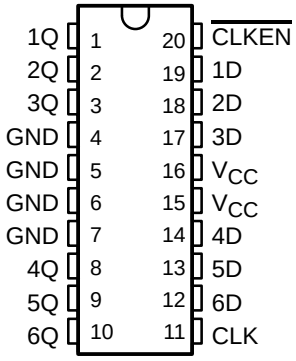
- **Inputs Are TTL-Voltage Compatible**
- **Contains Six D-Type Flip-Flops**
- **Clock Enable Latched to Avoid False Clocking**
- **Applications Include: Buffer/Storage Registers, Shift Registers, Pattern Generators**
- **Flow-Through Architecture Optimizes PCB Layout**
- **Center-Pin V_{CC} and GND Pin Configurations Minimize High-Speed Switching Noise**
- ***EPIC*™ (Enhanced-Performance Implanted CMOS) 1-μm Process**
- **500-mA Typical Latch-Up Immunity at 125°C**
- **Package Options Include Plastic Small-Outline Packages, and Standard Plastic 300-mil DIPs**

DW OR N PACKAGE
(TOP VIEW)



description

These circuits are positive-edge-triggered D-type flip-flops with a clock-enable input. Information at the D inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse if the clock-enable input ($\overline{\text{CLKEN}}$) is low.

Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going pulse. When the clock inputs are at either the high or low level, the data (D) input signal has no effect at the output. The circuits are designed to prevent false clocking by transitions at the clock-enable ($\overline{\text{CLKEN}}$) input.

The 74ACT11378 is characterized for operation from – 40°C to 85°C.

FUNCTION TABLE
(each flip-flop)

INPUTS			OUTPUT
$\overline{\text{CLKEN}}$	CLK	D	Q
H	X	X	Q_O
L	↑	H	H
L	↑	L	L
X	L	X	Q_O

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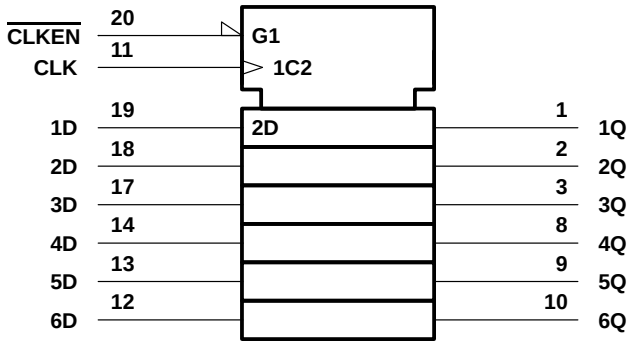
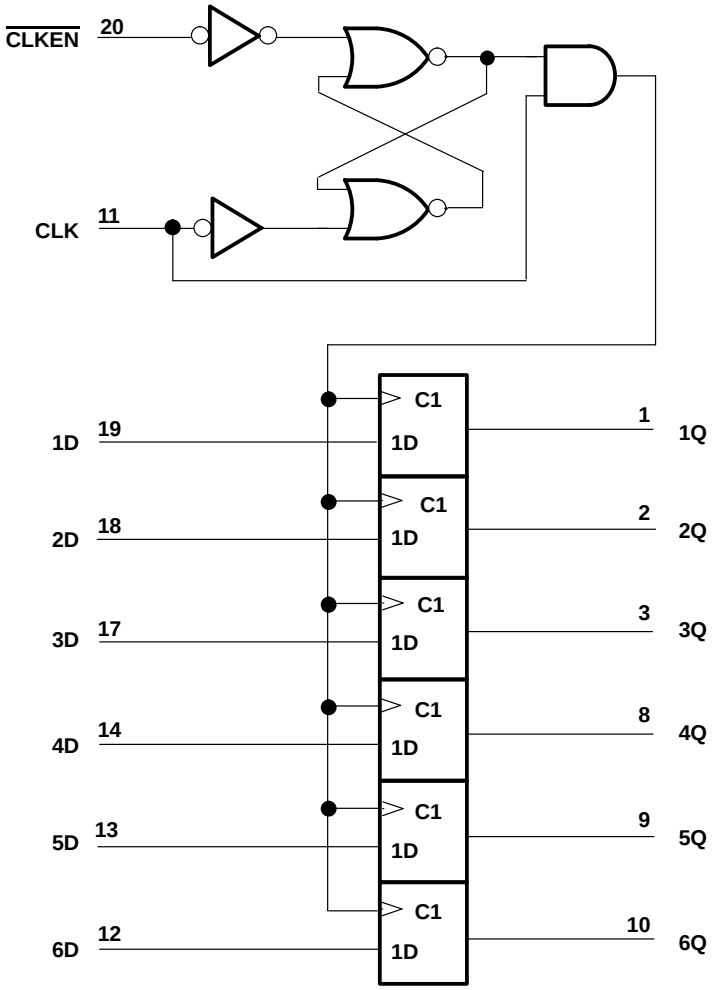
logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . . –0.5 V to 7 V
Input voltage range, V_I (see Note 1) . . . . . –0.5 V to V_{CC} + 0.5 V
Output voltage range, V_O (see Note 1) . . . . . –0.5 V to V_{CC} + 0.5 V
Input clamp current, I_{IK} (V_I < 0 or V_I > V_{CC}) . . . . . ±20 mA
Output clamp current, I_{OK} (V_O < 0 or V_O > V_{CC}) . . . . . ±50 mA
Continuous output current, I_O (V_O = 0 to V_{CC}) . . . . . ±50 mA
Continuous current through V_{CC} or GND pins . . . . . ±150 mA
Storage temperature range . . . . . –65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

recommended operating conditions (see Note 2)

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
V_I	Input voltage	0		V_{CC}	V
V_O	Output voltage	0		V_{CC}	V
I_{OH}	High-level output current			–24	mA
I_{OL}	Low-level output current			24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	ns/V
T_A	Operating free-air temperature	–40		85	°C

NOTE 2: Unused or floating inputs must be held high or low.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V_{CC}	T_A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
V_{OH}	I_{OH} = –50 µA	4.5 V	4.4			4.4		V
		5.5 V	5.4			5.4		
	I_{OH} = –24 mA	4.5 V	3.94			3.8		
		5.5 V	4.94			4.8		
	I_{OH} = –75 mA‡	5.5 V				3.85		
V_{OL}	I_{OL} = 50 µA	4.5 V			0.1		0.1	V
		5.5 V			0.1		0.1	
	I_{OL} = 24 mA	4.5 V			0.36		0.44	
		5.5 V			0.36		0.44	
	I_{OL} = 75 mA‡	5.5 V					1.65	
I_I	V_I = V_{CC} or GND	5.5 V			±0.1		±1	µA
I_{CC}	V_I = V_{CC} or GND, I_O = 0	5.5 V			8		80	µA
ΔI_{CC}§	One input at 3.4 V, Other inputs at V_{CC} or GND	5.5 V			0.9		1	mA
C_i	V_I = V_{CC} or GND	5 V		4.5				pF

‡ Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

§ This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 1)

			T_A = 25°C		MIN	MAX	UNIT
			MIN	MAX			
f_{clock}	Clock frequency		0	100	0	100	MHz
t_w	Pulse duration	CLK high or low	5		5		ns
t_{su}	Setup time, before CLK↑	Data	5		5		ns
		$\overline{\text{CLKEN}}$ high or low	4.5		4.5		
t_h	Hold time, after CLK↑	Data	0.5		0.5		ns
		$\overline{\text{CLKEN}}$ high or low	1		1		

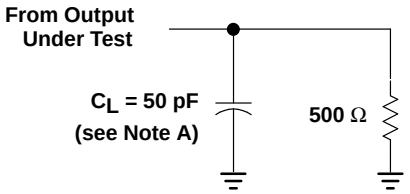
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T_A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
f_{max}			100	130		100		MHz
t_{PLH}	CLK	Any Q	2.8	5.9	6.8	2.8	9	ns
t_{PHL}			3.7	7.3	9.2	3.7	10.7	

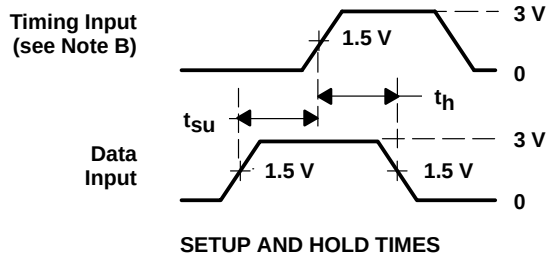
operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS		TYP	UNIT
C_{pd}	Power dissipation capacitance	C_L = 50 pF,	f = 1 MHz	31	pF

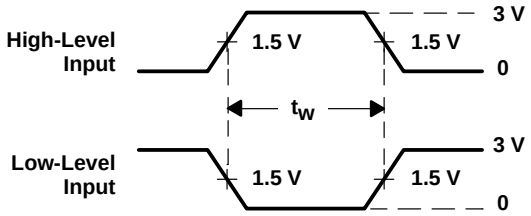
PARAMETER MEASUREMENT INFORMATION



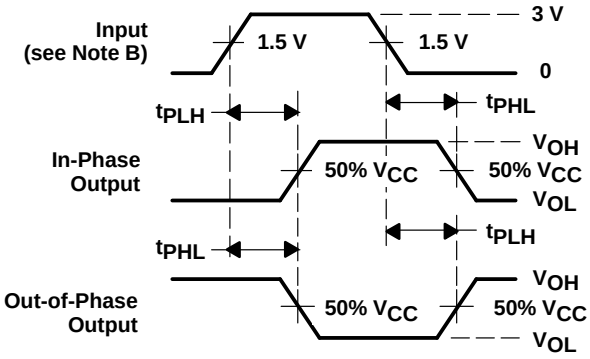
LOAD CIRCUIT



SETUP AND HOLD TIMES



PULSE DURATION



PROPAGATION DELAY TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. Input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r = 3 ns, t_f = 3 ns. For testing f_{max} and pulse duration: t_r = 1 to 3 ns, t_f = 1 to 3 ns.
C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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